



IntelliSense Test Platform

IntelliSense offers test and measurement services for various MEMS devices as well as related parameters during their fabrication process.

1. IntelliSense Measurement System for Pressure Sensor

- (1) Pressure regulator, Test chamber for high and low temperature, High accuracy voltage-stabilized source, Multimeter
- (2) Ability to measure sensor's nonlinearity, sensitivity, hysteresis loop, accuracy, temperature stability, etc..

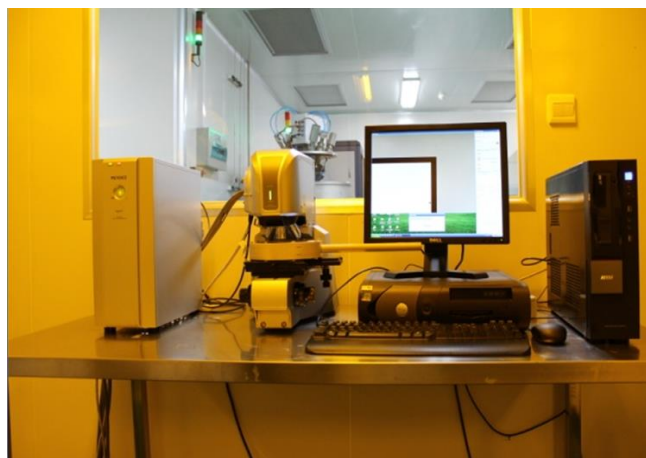


IntelliSense Measurement System for Pressure Sensor

2. Characterization for MEMS Devices

(1) Laser Scanning Microscope

Used for the accurate measurement of surface topography, 3D structure and cross-section profile on semiconductor devices.



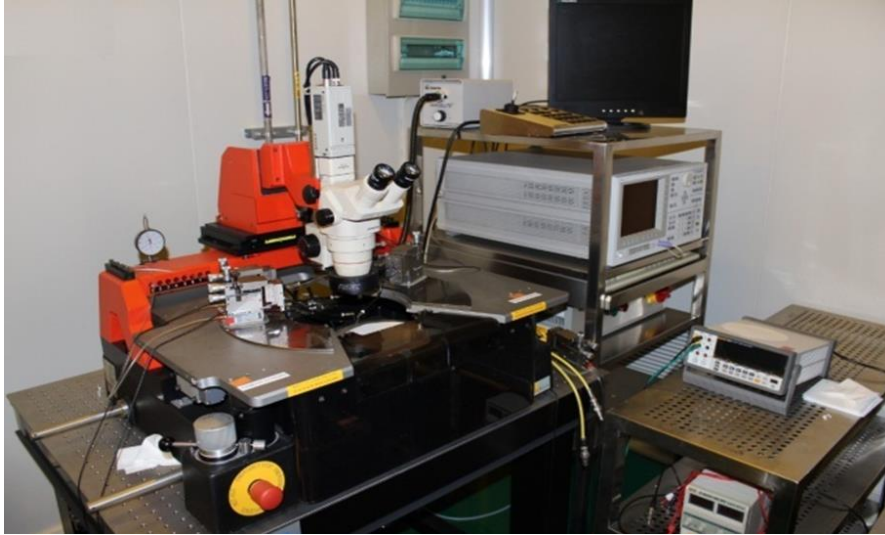
Laser Scanning Microscope





(2) Probe Stabilizer/ Semiconductor Parameters Test

Characterization of semiconductor devices. The Probe Stabilizer is mainly used for the electrical testing of devices, which is integrated with a pulse generator and switch selector. There is also a stress testing mode to ensure wafer reliability. It supports the measurement of capacitance in a quasi static. This stabilizer can help customers to have a reliable device quality, decrease the development time and the fabrication cost.



Probe Stabilizer/ Semiconductor Parameters testing instrument

(3) Membrane Testing Instrument

Accurate measurement of the single- or double-layer thickness on the silicon wafer. Layer material can be silicon dioxide, silicon nitride, silicon oxynitride, polysilicon etc..



Membrane Testing Instrument



(4) Profilometer

For the measurement of 2D surface topography. Step range: 0-130 μm , scanning range: 0-10mm.



Profilometer

(5) Semiconductor Logical Analyzer

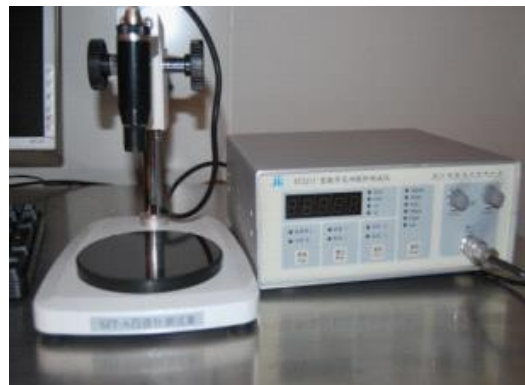
Mainly used for the measurement of the digital signal waveforms and also the generation of specific input pulses.



Semiconductor logical analyzer

(6) Sheet Resistance Testing Instrument

For your convenient and quick measurement of the thin film sheet resistance by the four probe method.



Resistance Testing Instrument